

## Thickness Dependence of Polarization Response in (Hf,Zr)O<sub>2</sub>

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Figures

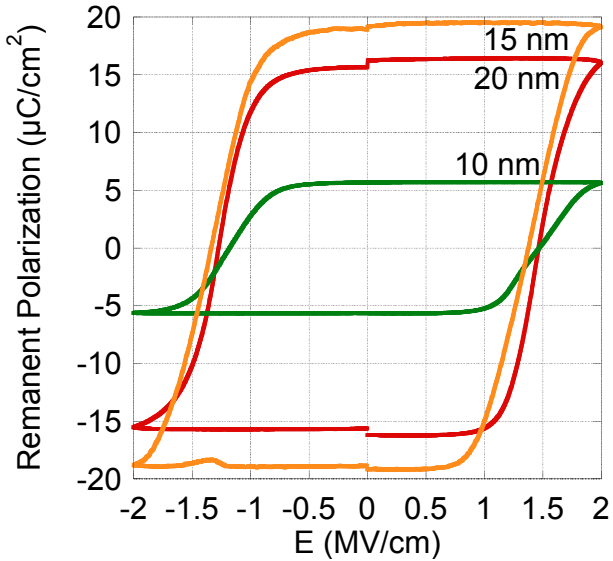


Figure 1: Remanent polarization vs electric field curves for 20, 15, and 10 nm Hf<sub>0.58</sub>Zr<sub>0.42</sub>O<sub>2</sub> films with TaN top and bottom electrodes calculated from positive up negative down polarization measurements.